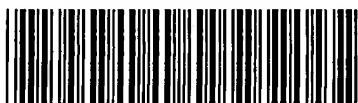


**Search Notes**

Application/Control No.

10/664,772

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under  
Reexamination

MASEL ET AL.

Art Unit

1745

**SEARCHED**

Class	Subclass	Date	Examiner
429	12	4/26/2007	DWY
429	34	4/26/2007	DWY
429	38	4/26/2007	DWY

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
429	12	4/26/2007	DWY
429	34	4/26/2007	DWY
429	38	4/26/2007	DWY

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	4/26/2007	DWY
Consult w/ W. Krynski and C. Tierney on the attribution declaration	4/26/2007	DWY